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LIST OF	LIST OF REFERENCES CITED BY APPLICANT APPLICANT Hideo ANDO et al.								
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Km.	AO	JP 5-158778	25 Jun 1993	Japan			х		
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iou.	AS	JP 9-182013	11 July 1997	Japan			х		
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conformance :	and no	t considered. Include c	opy of this form	with next communication	to applicant.	., III	uougii		

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				APPLICANT New Divisional Applica			ivisional Application	
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	AZ				Addi	tional Refe	rences sheet(s) attached	
Examiner 1 John Manual Date Considered 9/16/04						9/16/04		
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